

Application/Control No.	Applicant(s)/Patent under Reexamination
10/566,705	ICHIKAWA ET AL.
Examiner	Art Unit

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ICHIKAWA ET AL.		
	Art Unit	
	2123	

	SEARCHED		
Class	Subclass	Date	Examiner
703	22	12/29/2006	EHC
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INT	INTERFERENCE SEARCHED		
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Conducted inventors search	12/29/2006	EHC
East text search See attached	12/29/2006	EHC
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